

## Abstract

The invention relates to a device for checking or calibrating the angle-dependent alignment of a reference structure on a high-precision test-piece. The A device comprises a plinth, and a retainer piece, rotatably mounted ~~such as to rotate~~ about a retainer piece axis, for retaining the test-piece and a measuring piece with a measuring piece bearing unit, to rotationally mount ~~for the rotational mounting of~~ the measuring piece, about a measuring piece axis. An optical unit is mounted on the measuring piece, for receiving at least one test-piece beam, interacting with the reference structure on the test piece, running essentially in a measuring plane. The measuring piece bearing unit is arranged ~~to one side of the~~ on the measuring plane or to one side thereof ~~on the measuring plane~~. The measuring piece includes a base ~~form which is for a large part that is, for example,~~ axially symmetrical with the measuring piece axis encompassing or surrounding ~~and encompasses or surrounds~~ the intersection of the measuring piece axis with the retainer piece axis ~~on the measuring plane~~ and hence also encompasses or surrounds the test-piece.